ABSOLUTE MAXIMUM RATINGS

V _{CC} to GND0.3V to +4.0V	
IN_+, IN, OUT_+, OUT to GND0.3V to +4.0V	
EN_, SEL_, NC/RSEL to GND0.3V to (V_{CC} + 0.3V)	
Short-Circuit Duration (OUT_+, OUT)Continuous	
Continuous Power Dissipation ($T_A = +70^{\circ}C$)	
16-Pin SO (derate 8.7mW/°C above +70°C)696mW	

Storage Temperature Range	65°C to +150°C
Junction Temperature	+150°C
Operating Temperature Range	40°C to +85°C
Lead Temperature (soldering, 10s)	+300°C
ESD Protection	
Human Body Model IN + IN - OUT	+ OUT - +7kV

16-Pin TSSOP (derate 9.4mW/°C above +70°C)755mW

Human Body Model, IN_+, IN_-, OUT_+, OUT_-..... ±7kV

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

DC ELECTRICAL CHARACTERISTICS

 $(V_{CC} = +3.0V \text{ to } +3.6V, \text{ NC/RSEL} = \text{open for } R_L = 75\Omega \pm 1\%, \text{ NC/RSEL} = \text{high for } R_L = 100\Omega \pm 1\%, \text{ differential input voltage } |V_{\text{ID}}| = 100\Omega \pm 1\%$ 0.1V to V_{CC}, input voltage (V_{IN+}, V_{IN-}) = 0 to V_{CC}, EN_ = high, SEL0 = low, SEL1 = high, and T_A = -40°C to +85°C. Typical values at $V_{CC} = +3.3V$, $|V_{ID}| = 0.2V$, input common-mode voltage $V_{CM} = 1.2V$, $T_A = +25^{\circ}C$, unless otherwise noted.) (Note 1)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS		
LVCMOS/LVTTL INPUTS (EN_, SEL_)								
Input High Voltage	VIH		2.0		V _{CC}	V		
Input Low Voltage	VIL		GND		0.8	V		
Input High Current	Ιн	$V_{IN} = V_{CC} \text{ or } 2.0 \text{V}$	0		20	μΑ		
Input Low Current	١ _١ ٢	$V_{IN} = 0 \text{ or } 0.8 \text{V}$	-10		10	μΑ		
NC/RSEL INPUT								
Input High Voltage	VIH		2.0		V _{CC}	V		
Input Low Voltage	VIL		GND		0.8	V		
Input High Current	IIН	$V_{IN} = V_{CC} \text{ or } 2.0 \text{V}$	0		20	μΑ		
Input Low Current	١ _١ ٢	$V_{IN} = 0 \text{ or } 0.8 \text{V}$	-10		10	μΑ		
DIFFERENTIAL INPUTS (IN_+, IN_)							
Differential Input High Threshold	V _{TH}				100	mV		
Differential Input Low Threshold	V _{TL}		-100			mV		
		$V_{IN+} = V_{CC} \text{ or } 0, V_{IN-} = V_{CC} \text{ or } 0$	-1		1			
Input Current	I _{IN+} , I _{IN-}	$V_{IN+} = 3.6V \text{ or } 0, V_{IN-} = 3.6V \text{ or } 0, V_{CC} = 0$	-1		1	μA		
LVDS OUTPUTS (OUT_+, OUT)	•		•			•		
Differential Output Impedance		NC/RSEL = low or open	60	90	118			
(Note 2)	RDIFF	NC/RSEL = high	85	122	155	Ω		
		$R_L = 75\Omega$, NC/RSEL = open, Figure 1	280	382	470			
Differential Output Voltage	VOD	$R_L = 100\Omega$, NC/RSEL = high, Figure 1	200	302	470	mV		
Change in Magnitude of V _{OD}		$R_L = 75\Omega$, NC/RSEL = open, Figure 1			25	mV		
Between Complementary Output States	ΔV_{OD}	$R_L = 100\Omega$, NC/RSEL = high, Figure 1			25	mv		
Offeet Common Made Valters		$R_L = 75\Omega$, NC/RSEL = open, Figure 1	1.150		1 400	V		
Offset Common-Mode Voltage	Vos	$R_L = 100\Omega$, NC/RSEL = high, Figure 1	1.150		1.430	v		
Change in Magnitude of V _{OS}		$R_L = 75\Omega$, NC/RSEL = open, Figure 1			05	mV		
Between Complementary Output States	ΔV_{OS}	$R_L = 100\Omega$, NC/RSEL = high, Figure 1			25			

M/XI/M

DC ELECTRICAL CHARACTERISTICS (continued)

 $(V_{CC} = +3.0V \text{ to } +3.6V, \text{ NC/RSEL} = \text{open for } R_L = 75\Omega \pm 1\%, \text{ NC/RSEL} = \text{high for } R_L = 100\Omega \pm 1\%, \text{ differential input voltage } |V_{ID}| = 0.1V \text{ to } V_{CC}, \text{ input voltage } (V_{IN+}, V_{IN-}) = 0 \text{ to } V_{CC}, \text{ EN}_{-} = \text{high}, \text{ SEL0} = \text{low}, \text{ SEL1} = \text{high}, \text{ and } T_A = -40^{\circ}\text{C} \text{ to } +85^{\circ}\text{C}. \text{ Typical values at } V_{CC} = +3.3V, |V_{ID}| = 0.2V, \text{ input common-mode voltage } V_{CM} = 1.2V, T_A = +25^{\circ}\text{C}, \text{ unless otherwise noted.}) (Note 1)$

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
Output Short-Circuit Current		V_{ID} = +100mV, V_{OUT_+} = 0, other output open		-12	-20	mA
Output Short-Circuit Current	IOS	$V_{ID} = -100 \text{mV}, V_{OUT_{-}} = 0,$ other output open			-20	ШA
Both Output Short-Circuit Current	IOSB	$V_{ID} = +100mV, V_{OUT_+} = 0, V_{OUT} = 0$		-12	-20	mA
	IO2B	$V_{ID} = -100 \text{mV}, V_{OUT_+} = 0, V_{OUT} = 0$		-12	-20	ША
Output High-Z Current	I _{OZ+} , I _{OZ-}	Disabled, V _{OUT_+} = V _{CC} or 0, V _{OUT} = V _{CC} or 0	-1		1	μΑ
Power-Off Output Current	IOFF+, IOFF-	$V_{CC} = 0, V_{OUT_+} = 3.6V \text{ or } 0, V_{OUT} = 3.6V \text{ or } 0$	-1		1	μΑ
SUPPLY CURRENT						
		R_L = 75 Ω, C_L = 5pF, enabled, quiescent, Figure 5		38	55	
Supply Current		R_L = 100 Ω,C_L = 5pF, enabled, quiescent, Figure 5		33	50	~^^
Supply Current	Icc	R_L = 75 Ω , C_L = 5pF, enabled, switching at 400MHz (800Mbps), Figure 5 (Note 2)		58	70	mA
		R_L = 100 Ω,C_L = 5pF, enabled, switching at 400MHz (800Mbps), Figure 5 (Note 2)		52	65	
High-Z Supply Current	ICCZ	Disabled		15	25	mA

AC ELECTRICAL CHARACTERISTICS

 $(V_{CC} = +3.0V \text{ to } +3.6V, \text{NC/RSEL} = \text{open for } R_L = 75\Omega \pm 1\%, \text{NC/RSEL} = \text{high for } R_L = 100\Omega \pm 1\%, \text{C}_L = 5\text{pF}, \text{ differential input voltage}$ $|V_{ID}| = 0.15V \text{ to } V_{CC}, \text{EN}_{-} = \text{high}, \text{SEL0} = \text{low}, \text{SEL1} = \text{high, differential input transition time} = 0.6\text{ns}$ (20% to 80%), input voltage $(V_{IN+}, V_{IN-}) = 0$ to V_{CC} , LVCMOS/LVTTL inputs = 0 to 3V with 2ns (10% to 90%) transition times, $T_A = -40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$. Typical values at $V_{CC} = +3.3V$, $|V_{ID}| = 0.2V$, $V_{CM} = 1.2V$, $T_A = +25^{\circ}\text{C}$, unless otherwise noted.) (Notes 3, 4)

PARAMETER	SYMBOL	CONDITIONS	MIN	ТҮР	MAX	UNITS
Input to SEL Setup Time (Note 5)	t SET	Figures 2, 3	0.4			ns
Input to SEL Hold Time (Note 5)	t HOLD	Figures 2, 3	0.6			ns
SEL to Switched Output	tswitch	Figures 2, 3	1.8	2.5	3.5	ns
Disable Time High to Z	t _{PHZ}	Figure 4			3.8	ns
Disable Time Low to Z	t _{PLZ}	Figure 4			3.8	ns
Enable Time Z to High	t _{PZH}	Figure 4			3.2	ns
Enable Time Z to Low	t _{PZL}	Figure 4			3.2	ns
Propagation Law to High Dalay	to:	Figures 5, 6	1.7	2.3	3.4	20
Propagation Low-to-High Delay	^t PLHD	$V_{CC} = +3.3V$, $T_A = +25^{\circ}C$; Figures 5, 6	2.0	2.3	2.9	ns
Propagation High to Law Dalay	to:	Figures 5, 6	1.7	2.3	3.4	20
Propagation High-to-Low Delay	^t PHLD	$V_{CC} = +3.3V$, $T_A = +25^{\circ}C$; Figures 5, 6	2.0	2.3	2.9	ns

AC ELECTRICAL CHARACTERISTICS (continued)

 $(V_{CC} = +3.0V \text{ to } +3.6V, \text{NC/RSEL} = \text{open for } R_L = 75\Omega \pm 1\%, \text{NC/RSEL} = \text{high for } R_L = 100\Omega \pm 1\%, \text{C}_L = 5\text{pF}, \text{ differential input voltage}$ $|V_{|D}| = 0.15V \text{ to } V_{CC}, \text{EN}_{-} = \text{high}, \text{SEL0} = \text{low}, \text{SEL1} = \text{high, differential input transition time} = 0.6\text{ns}$ (20% to 80%), input voltage $(V_{|N+}, V_{|N-}) = 0$ to $V_{CC}, \text{LVCMOS/LVTTL inputs} = 0$ to 3V with 2ns (10% to 90%) transition times, $T_A = -40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$. Typical values at $V_{CC} = +3.3V, |V_{|D}| = 0.2V, V_{CM} = 1.2V, T_A = +25^{\circ}\text{C}, \text{ unless otherwise noted.}$ (Notes 3, 4)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
Pulse Skew ItpLHD -tpHLDI (Note 6)	t SKEW	Figures 5, 6		25	90	ps
Output Channel-to-Channel Skew	tccs	Figures 5, 7		20	50	ps
Output Low-to-High Transition Time (20% to 80%)	t _{LHT}	Figures 5, 6	160	270	480	ps
Output High-to-Low Transition Time (20% to 80%)	thlt	Figures 5, 6	160	270	480	ps
LVDS Data Path Peak-to-Peak	tur	V_{ID} = 200mV, V_{CM} = 1.2V, 50% duty cycle, 800Mbps, input transition time = 600ps (20% to 80%)		10	30	
Jitter (Note 7)	tji⊤	V_{ID} = 200mV, V_{CM} = 1.2V, PRBS = 2 ²³ -1 data pattern, 800Mbps, input transition time = 600ps (20% to 80%)		65	120	ps

Note 1: Current into a pin is defined as positive. Current out of a pin is defined as negative. All voltages are referenced to ground except V_{TH}, V_{TL}, V_{ID}, V_{OD}, and ΔV_{OD}.

Note 2: Guaranteed by design and characterization, not production tested.

Note 3: AC parameters are guaranteed by design and characterization.

Note 4: CL includes scope probe and test jig capacitance.

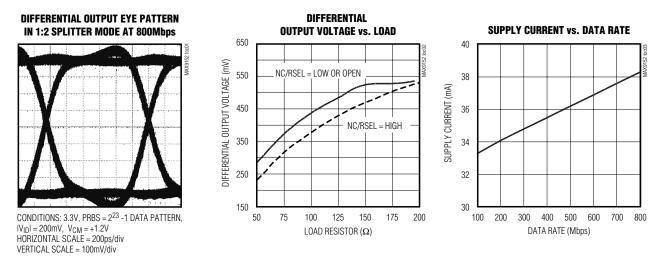
Note 5: t_{SET} and t_{HOLD} time specify that data must be in a stable state before and after the SEL transition.

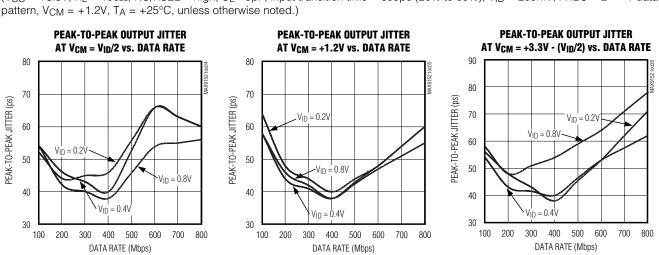
Note 6: tSKEW is the magnitude difference of differential propagation delay over rated conditions; tSKEW = ltPHLD - tPLHDl.

Note 7: Specification includes test equipment jitter.

Typical Operating Characteristics

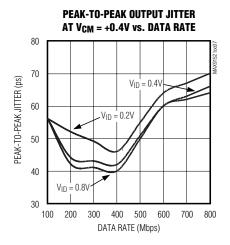
 $(V_{CC} = +3.3V, R_L = 100\Omega, NC/RSEL = high, C_L = 5pF$, input transition time = 600ps (20% to 80%), $V_{ID} = 200mV$, PRBS = 2^{23} - 1 data pattern, $V_{CM} = +1.2V$, $T_A = +25^{\circ}C$, unless otherwise noted.)

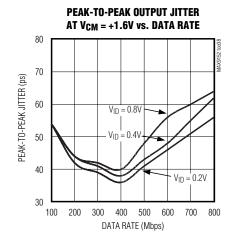




Typical Operating Characteristics (continued)

 $(V_{CC} = +3.3V, R_L = 100\Omega, NC/RSEL = high, C_L = 5pF$, input transition time = 600ps (20% to 80%), $V_{ID} = 200mV$, PRBS = 2^{23} - 1 data pattern, $V_{CM} = +1.2V$, $T_A = +25^{\circ}C$, unless otherwise noted.)





Pin Description

PIN	NAME	FUNCTION
1, 2	SEL1, SEL0	LVCMOS/LVTTL Logic Inputs. Allow the switch to be configured as a mux, repeater, or splitter.
3, 4	IN0+, IN0-	LVDS/LVPECL Differential Input 0
5	V _{CC}	Power-Supply Input. Bypass V _{CC} to GND with 0.1 μ F and 0.001 μ F ceramic capacitors.
6, 7	IN1+, IN1-	LVDS/LVPECL Differential Input 1
8	NC/RSEL	Logic Input. Selects differential output resistance. Set NC/RSEL to open or low when $R_L = 75\Omega$, set to high when $R_L = 100\Omega$.
9	NC	No Connect
10, 11	OUT1-, OUT1+	LVDS Differential Output 1
12	GND	Ground
13, 14	OUT0-, OUT0+	LVDS Differential Output 0
15, 16	EN1, ENO	LVCMOS/LVTTL Logic Inputs. Enables or disables the outputs. Setting EN0 or EN1 high enables the corresponding output, OUT0 or OUT1. Setting EN0 or EN1 low puts the corresponding output into high impedance (differential output resistance is also high impedance).

Detailed Description

The LVDS interface standard is a signaling method intended for point-to-point communication over a controlled impedance medium as defined by the ANSI TIA/EIA-644 and IEEE 1596.3 standards. LVDS uses a lower voltage swing than other common communication standards, achieving higher data rates with reduced power consumption while reducing EMI emissions and system susceptibility to noise.

The MAX9152 is an 800Mbps 2 x 2 crosspoint switch designed for high-speed, low-power point-to-point and multidrop interfaces. The device accepts LVDS or differential LVPECL signals and routes them to outputs depending on the selected mode of operation.

A differential input with a magnitude of 0.1V to V_{CC} with single-ended voltage levels at or within the MAX9152's V_{CC} and ground switches the output. A differential input with a magnitude of at least 0.15V with single-ended voltage levels at or within the MAX9152's V_{CC} and ground is required to meet the AC specifications.

In the 1:2 splitter mode, the outputs repeat the selected input. This is useful for distributing a signal or creating a copy for use in protection switching. In the repeater

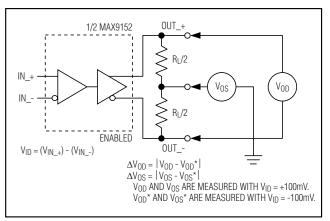


Figure 1. Test Circuit for V_{OD} and V_{OS}

mode, the device operates as a two-channel buffer. Repeating restores signal amplitude, allowing isolation of media segments or longer media drive. The device is a crosspoint switch where any input can be connected to any output or outputs. In 2:1 mux mode, primary and backup signals can be selected to provide a protection-switched, fault-tolerant application.



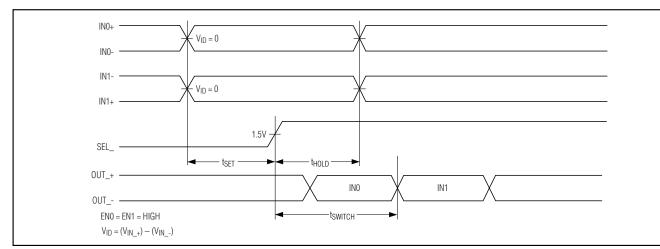


Figure 2. Input to Rising Edge Select Setup, Hold, and Mux Switch Timing Diagram

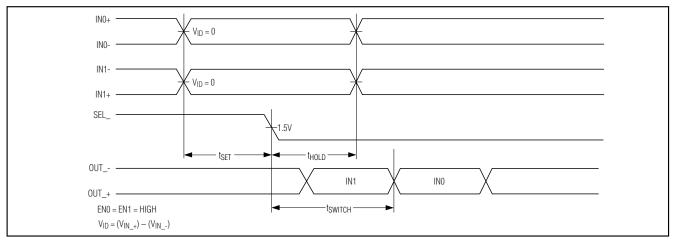


Figure 3. Input to Falling Edge Select Setup, Hold, and Mux Switch Timing Diagram

Input Fail-Safe

The differential inputs of the MAX9152 do not have internal fail-safe biasing. If fail-safe biasing is required, it can be implemented with external large-value resistors. IN_+ should be pulled up to V_{CC} with 10k Ω and IN_ should be pulled down to GND with 10k Ω . The voltage-divider formed by the 10k Ω resistors and the 100 Ω termination resistor (across IN_+ and IN_-) provides a slight positive differential bias and sets a high state at the device output when inputs are undriven.

Output Resistance

The MAX9152 has a selectable differential output resistance to reduce reflections from impedance discontinuities in the interconnect. Reflections are reduced, compared to a high-impedance output. A termination resistor at the receiver is still required and is the primary termination for the interconnect. Select the output resistance that best matches the differential characteristic impedance of the interconnect used.

Select Function

The SEL0 and SEL1 logic inputs allow the device to be configured as a high-speed differential crosspoint, 2:1 mux, 1:2 demux, dual repeater, or 1:2 splitter (Figure 8). See Table 1 for mode selection settings.

Enable Function

The EN0 and EN1 logic inputs enable and disable driver outputs OUT0 and OUT1. Setting EN0 or EN1 high enables the corresponding driver output. Setting EN0



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or EN1 low puts the corresponding driver output into a high-impedance state (the differential output resistance also becomes high impedance).

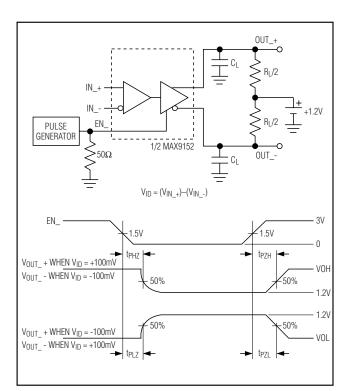


Figure 4. Output Active to High-Z and High-Z to Active Test Circuit and Timing Diagram

Table 1. Input/Output Function Table

SEL0	SEL1	OUT0	OUT1	MODE
L	L	IN0	INO	1:2 splitter
L	Н	IN0	IN1	Repeater
Н	L	IN1	IN0	Switch
Н	Н	IN1	IN1	1:2 splitter

Applications Information

Unused Differential Inputs

Unused differential inputs should be tied to ground and V_{CC} to prevent the high-speed input stage from switching due to noise. IN_+ should be pulled to V_{CC} with 10k Ω and IN_- should be pulled to GND with 10k Ω .

Expanding the Number of LVDS Output Ports

Devices can be cascaded to make larger switches. Total propagation delay and total jitter should be considered to determine the maximum allowable switch size. Three MAX9152s are needed to make a 2 input x 4 output crosspoint switch with two device propagation delays. Seven MAX9152s make a 2 input x 8 output crosspoint with three device delays.

Accepting PECL Inputs

The inputs accept PECL signals with the use of an attenuation circuit, as shown in Figure 9.

Power-Supply Bypassing

Bypass V_{CC} to ground with high-frequency surfacemount ceramic 0.1μ F and 0.001μ F capacitors in paral-

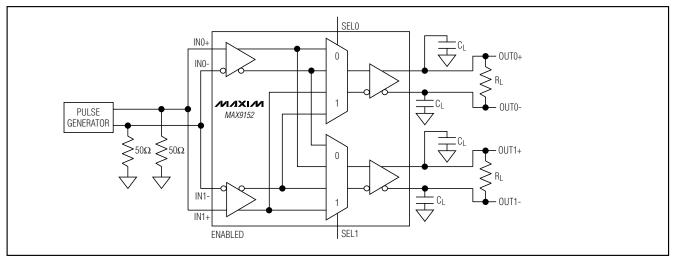


Figure 5. Output Transition Time, Propagation Delay, and Output Channel-to-Channel Skew Test Circuit

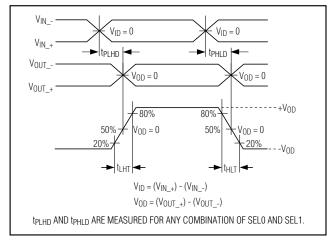


Figure 6. Output Transition Time and Propagation Delay Timing Diagram

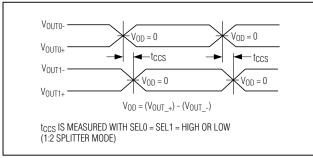


Figure 7. Output Channel-to-Channel Skew

lel as close to the device as possible, with the smaller value capacitor closest to $V_{\mbox{CC}}.$

Differential Traces

Trace characteristics affect the performance of the MAX9152. Use controlled-impedance traces. Eliminate reflections and ensure that noise couples as common mode by running the differential trace pairs close together. Reduce skew by matching the electrical length of the traces. Excessive skew can result in a degradation of magnetic field cancellation.

Maintain the distance between the differential traces to avoid discontinuities in differential impedance. Avoid 90° turns and minimize the number of vias to further prevent impedance discontinuities.

Cables and Connectors

Transmission media should have nominal differential impedance of 75 Ω or 100 Ω . Use cables and connectors that have matched differential impedance to minimize impedance discontinuities.

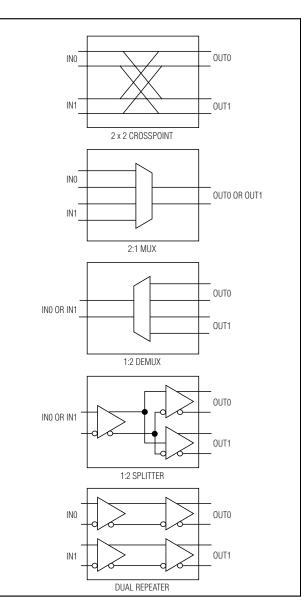


Figure 8. Programmable Configurations

Avoid the use of unbalanced cables such as ribbon or simple coaxial cable. Balanced cables such as twisted pair offer superior signal quality and tend to generate less EMI due to canceling effects. Balanced cables tend to pick up noise as common mode, which is rejected by the differential receiver.

Board Layout

For LVDS applications, a four-layer printed-circuit (PC) board that provides separate power, ground, and signal planes is recommended.



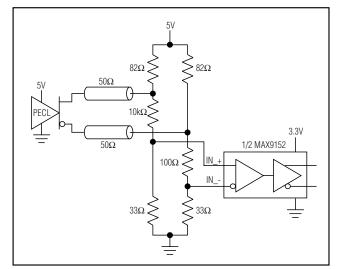
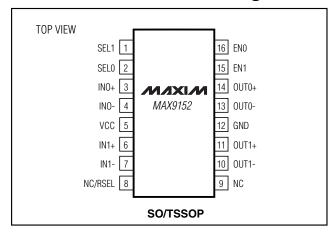


Figure 9. PECL to LVDS Level Conversion Network

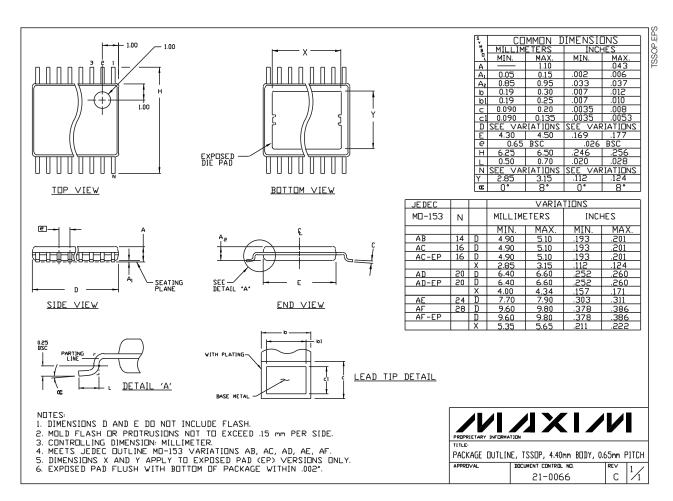


Pin Configuration

Chip Information

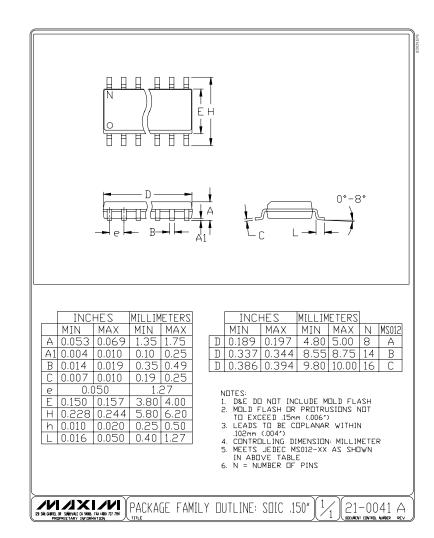
TRANSISTOR COUNT: 880 PROCESS: CMOS

Package Information



M/IXI/N

Package Information (continued)



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MAX9152

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